

|                                   |                                       |   |             |
|-----------------------------------|---------------------------------------|---|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>09/895,866 | Applicant(s)/Patent Under<br>Reexamination<br>SAMBASIVAN ET AL. |             |
|                                   | Examiner<br>Colleen P Cooke           | Art Unit<br>1725  | Page 1 of 1 |

**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name              | Classification |
|---|---|--|-----------------|-------------------|----------------|
|   | A | US-6,447,714                                     | 09-2002         | Goyal et al.      | 419/28         |
|   | B | US-6,573,209                                     | 06-2003         | Sambasivan et al. | 501/96.1       |
|   | C | US-6,537,689                                     | 03-2003         | Schoop et al.     | 428/701        |
|   | D | US-6,337,991                                     | 01-2002         | Li et al.         | 505/161        |
|   | E | US-6,190,752                                     | 02-2001         | Do et al.         | 428/141        |
|   | F | US-6,180,570                                     | 01-2001         | Goyal, Amit       | 505/236        |
|   | G | US-5,453,306                                     | 09-1995         | Tatsumi et al.    | 427/569        |
|   | H | US-  |                 |                   |                |
|   | I | US-  |                 |                   |                |
|   | J | US-  |                 |                   |                |
|   | K | US-  |                 |                   |                |
|   | L | US-  |                 |                   |                |
|   | M | US-  |                 |                   |                |

**FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)   |
|---|---|---|
|   | U | Kumar et al., "Enhancement in critical current density of Y1Ba2Cu3O(7-beta) thin films on hastelloy with TiN buffer layers"<br>Applied Physics Letters, August 24, 1992, Volume 61, Issue 8, pp. 976-978. |
|   | V |   |
|   | W |   |
|   | X |   |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.